



BSI Standards Publication

Semiconductor devices - Mechanical and climatic test methods

Part 43: Guidelines for IC reliability qualification plans (IEC 60749-43:2017)

National foreword

This British Standard is the UK implementation of EN 60749-43:2017. It is identical to IEC 60749-43:2017.

The UK participation in its preparation was entrusted to Technical Committee EPL/47, Semiconductors.

A list of organizations represented on this committee can be obtained on request to its secretary.

This publication does not purport to include all the necessary provisions of a contract. Users are responsible for its correct application.

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